

## Week 13: Drift & Diffusion Announcements

## Drift & Diffusion of Carriers

- Last class we talked about qualitatively how drift and diffusion in a pn junction led to a built in voltage across the junction
- This built in voltage is what:
  - Causes a turn on voltage for diodes
  - Results in rectifying IV curve for a diode
  - Allows a solar cell to result in an output of current (rather than the solar generated electrons and holes recombining)

## What causes diffusion?

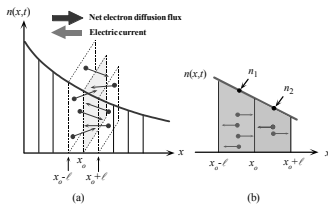


Fig. 5.29: (a) Arbitrary electron concentration  $n(x)$  profile in a semiconductor. There is a net diffusion (flux) of electrons from higher to lower concentrations. (b) Expanded view of two adjacent sections at  $x_0$ . There are more electrons crossing  $x_0$  coming from left ( $x_0 - \ell$ ) than coming from right ( $x_0 + \ell$ ).

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## Mathematical Look at Diffusion

$$\Gamma = \frac{\Delta N}{A \Delta t}$$

$$J = Q\Gamma$$

$$\Gamma_e = \frac{\frac{1}{2} n_1 \ell - \frac{1}{2} n_2 \ell}{\tau} = -\frac{\ell}{2\tau} (n_2 - n_1)$$

$$(n_2 - n_1) = \frac{dn}{dx} \Delta x = \frac{dn}{dx} \ell$$

$$\Gamma_e = -\frac{\ell^2}{2\tau} \frac{dn}{dx} = -D \frac{dn}{dx}$$

## D for Electrons & Holes

Q = -e for electrons  
 +e for holes

$$J = Q\Gamma$$

$$\Gamma_e = -D_e \frac{dn}{dx} \longrightarrow$$

$$\Gamma_h = -D_h \frac{dp}{dx}$$

## Einstein's Relation

- Einstein's relation relates the diffusion coefficient (D) of electron and holes to the electron and hole mobility

# Photoconduction Example

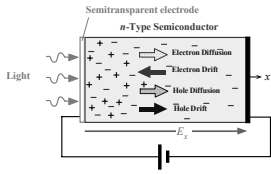


Fig. 5.31: When there is an electric field and also a concentration gradient, charge carriers move both by diffusion and drift. ( $E_x$  is the electric field.)  
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# Drift and Diffusion

- In photoconduction example:

$$J_e = en\mu_e E_x + eD_e \frac{dn}{dx}$$

$$J_h = ep\mu_h E_x - eD_h \frac{dp}{dx}$$

# Resulting Built-in Voltage

- The built-in voltage results from the drift and diffusion terms equilibrating (canceling each other out)

$$J_e = en\mu_e E_x + eD_e \frac{dn}{dx} = -en\mu_e \frac{dV}{dx} + eD_e \frac{dn}{dx} = 0$$

$$\frac{e kT\mu_e}{e} \frac{dn}{dx} = en\mu_e \frac{dV}{dx}$$

$$\int_{V_1}^{V_2} dV = \frac{kT}{e} \int_{n_1}^{n_2} \frac{dn}{n}$$

$$V_2 - V_1 = \frac{kT}{e} \ln\left(\frac{n_2}{n_1}\right)$$

# Continuity Equation

- We are also often concerned with a change in the carrier concentration with time
  - This is what results when carriers diffuse or drift away
- The continuity equation quantifies the change in carriers with time as a function of location
- Steady state continuity equation is when the total amount of carriers is conserved (none is being added or subtracted)

# Continuity Equation for Holes

$$\frac{\partial p_n}{\partial t} = -\frac{1}{e} \left( \frac{\partial J_h}{\partial x} \right) - \frac{p_n - p_{no}}{\tau_h} + G_{ph}$$

$e$  = electronic charge ( $1.60218 \times 10^{-19}$  C),  $J_h$  = hole current due to drift and diffusion,  $x$  = position,  $p_n$  = hole concentration in an  $n$ -type semiconductor,  $p_{no}$  = equilibrium minority carrier (hole concentration in an  $n$ -type semiconductor) concentration,  $\tau_h$  = hole recombination time (lifetime),  $G_{ph}$  = photogeneration rate at  $x$  at time  $t$ ,  $t$  = time

# Continuity Equation with Uniform Photogeneration

$$\frac{\partial \Delta p_n}{\partial t} = -\frac{\Delta p_n}{\tau_h} + G_{ph}$$

$\Delta p_n = p_n - p_{no}$  is the excess hole concentration,  $t$  = time,  $\tau_h$  = hole recombination time (lifetime),  $G_{ph}$  = photogeneration rate at  $x$  at time  $t$

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# Steady State Decay in Minority Carrier Lifetime

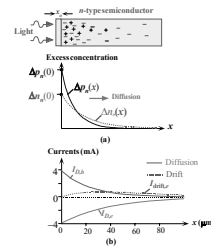


Fig. 5.34: (a) Steady state excess carrier concentration profiles in an  $n$ -type semiconductor that is continuously illuminated at one end. (b) Minority and majority carrier current components in open circuit. Total current is zero.  
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## Steady State Decay in Minority Carrier Lifetime

$$\frac{\partial p_n}{\partial t} = -\frac{1}{e} \left( \frac{\partial J_h}{\partial x} \right) = -\frac{p_n - p_{no}}{\tau_h}$$

$$\Delta p_n(x) = \Delta p_n(x=0) \exp\left(-\frac{x}{L_h}\right)$$

$$L_h = \sqrt{D_h \tau_h}$$